



## Digitalization of Metrology

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submissions:

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### Message from the Guest Editors

Dear Colleagues,

The digitalization of metrology is a hot topic in the area of international measurement. BIPM, ISO, IEC, and other international organizations are aiming towards the Digital Transformation of metrology. NIST, PTB, NIM, and other national institutes are all developing digitalizations of metrology. The digitalization of metrology is maintaining and building confidence in the accuracy and global comparability of measurements.

The aim of the Special Issue focuses on frontier research on the digitalization of metrology. Any research on the DT of metrology or measurements is invited to be submitted to this Special Issue; Research areas may include (but are not limited to) the following:

- Metrology digitalization research;
- Digital representations of physical quantities and units of measurement, such as D-SI;
- Computations with physical quantities;
- Information retrieval and knowledge representations (semantics, ontologies, etc.).

We look forward to receiving your contributions.

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*Guest Editors*





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## Editor-in-Chief

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## Message from the Editor-in-Chief

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